

Bucket No. 292393US2PCT



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Laurent PAIN

SERIAL NO: 10/582,791

GAU:

FILED: June 14, 2006

EXAMINER:

FOR: METHOD FOR REPAIRING ERRORS OF PATTERNS EMBODIED IN THIN LAYERS

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
292393US2PCTSERIAL NO.
10/582,791

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Laurent PAINFILING DATE
June 14, 2006

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	2003 039923	02-27-03	MANGAT, Pawitter et al.			
	AB	6 596 465	07-22-03	MANGAT, Pawitter Jit Singh et al.			
	AC	2003 027053	02-06-03	YAN, Pèi-yang			
	AD	2002 122995	09-05-02	MANCINI, David P. et al.			
	AE	5 945 238	08-31-99	HUGGINS, Alan H. et al.			
	AF	5 985 518	11-16-99	HUGGINS, Alan H. et al.			
	AG	5 953 577	09-14-99	HUGGINS, Alan H. et al.			
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	60 142518	12-03-85	JP (with English abstract)		NO
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	LIPP, S. et al., "A Comparison of Focused Ion Beam and Electron Beam Induced Deposition Processes", Microelectron. Reliab., Vol. 36, No. 11/12, pgs. 1779-1782, 1996.
	AX	WARD, B.W. et al., "Repair of Photomasks with Focussed Ion Beams", SPIE, Vol. 537, pgs. 110-116, 1985.
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



U.S. PCT Application Serial No: 10/582,791

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Laurent PAIN

Docket No. 292393US2PCT

STATEMENT OF RELEVANCY

- 1) References AA-AG and AO have been cited in the International Search Report. A copy of these references is being submitted herewith.
- 2) References have been cited in the corresponding Search Report. A copy of these references is being submitted herewith.
- 3) References are discussed in the specification. A copy of these references is being submitted herewith.
- 4) References AW-AX are additional prior art known to Applicant. A copy of these references is being submitted herewith.